


<b>Search Notes</b>  	<b>Application/Control No.</b>  10578504	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  HONGMIN FAN	<b>Art Unit</b>  2612

SEARCHED			
Class	Subclass	Date	Examiner
340	572.7, 445-448	4/23/2008	HF
343	711-717	4/23/2008	HF

SEARCH NOTES		
Search Notes	Date	Examiner
J. Hofsass	4/22/2008	HF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner